



For Immediate Release

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**AEHR TEST SYSTEMS SCHEDULES FOURTH QUARTER
FISCAL YEAR 2009 EARNINGS RELEASE AND CONFERENCE CALL**

Fremont, CA (July 15, 2009) - Aehr Test Systems (Nasdaq: AEHR), a technology leader in the semiconductor test and burn-in equipment industry, today announced that it will report financial results for the fourth quarter of fiscal 2009 ended May 31, 2009 after the market closes on Tuesday, July 28, 2009.

Management of Aehr Test Systems will host a conference call and webcast that same day at 5:00 p.m. Eastern (2:00 p.m. Pacific) to discuss the Company's operating performance. The conference call will be accessible live via the internet at www.aehr.com. Please go to the website at least 15 minutes before start time to register, download and install any necessary audio software. A replay of the webcast will be available at www.aehr.com for 90 days.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAMs, flash, and other memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the ABTS™, FOX™, MTX and MAX systems and the DiePak® carrier. The ABTS is Aehr Test's newest system for packaged part test during burn-in for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

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